

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Stephen J. Hudgens

Group Art Unit:

Serial No .:

10/633,873

§ Examiner:

Filed:

August 1, 2003

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For:

Processing Phase Change Material To

Improve Programming Speed

Atty. Dkt. No.:

ITO.0048US (P16245)

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

## **INFORMATION DISCLOSURE STATEMENT**

Dear Sir:

Applicant submits the references listed on the attached form PTO 1449 together with any required copies of such references.

This statement is being filed within three months of the filing date of the application. Please apply any charges or credits to Deposit Account No. 20-1504 (ITO.0048US).

Respectfully submitted,

Date:  $\frac{10/3\pi/03}{3\pi}$ 

Timothy My. Trop, Reg. No. 28,994

TROP, PRUNER & HU, P.C. 8554 Katy Freeway, Suite 100

Houston, Texas 77024

(713) 468-8880 [Phone]

(713) 468-8883 [Fax]

Date of Deposit: 10-30-03

I hereby certify under 37 CFR 1.8(a) that this correspondence is being deposited with the United States Postal Service as **first class mail** with sufficient postage on the date indicated above and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA

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**Sherry Tipton** 

## ATTY DOCKET NO. SERIAL NO. ITO.0048US (P16245) 10/633,873 APPLICANT(S): INFORMATION DISCLOSURE CITATION STEPHEN J. HUDGENS (Use several sheets if necessary) FILING DATE: GROUP ART UNIT: August 1, 2003 **U.S. PATENT DOCUMENTS** \*EXAMINER FILING DATE DOCUMENT NUMBER NAME CLASS **SUBCLASS** INITIAL IF APPROPRIATE A. B. C. D. FOREIGN PATENT DOCUMENTS **TRANSLATION** DATE DOCUMENT NUMBER COUNTRY CLASS **SUBCLASS** YES NO E. F. G. OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) Hwang, Y.N., Hong, J.S., Lee, S.H., Ahn, S.J., Jeong, G.T., Koh, G.H., Kim, H.J., Jeong, W.C., Lee, S.Y., Park, J.H., Ryoo, K.C., Horii, H., Ha, Y.H., Yi, J.H., Cho, W.Y., Kim, Y.T., Lee, K.H., Joo, S.H., Park, S.O., Jeong, U.I., Jeong, H.S. and Kim, Kinam, "Completely CMOS-Compatible Phase-Change Nonvolatile RAM Using NMOS Cell Transistors," presented at 2003 19th IEEE Non-Volatile Semiconductor Memory Workshop, Monterey, California, February 26-20, 2003 Ha, Y.H., Yi, J.H., Horii, H., Park, J.H., Joo, S.H., Park, S.O., Chung, U-In and Moon, J.T., "An Edge ١. Contact Type Cell for Phase Change RAM Featuring Very Low Power Consumption," presented at IEEE 2003 Symposium on VLSI Technology, Kyoto, Japan, June 12-14, 2003 J. Hwang, Y.N., Hong, J.S., Lee, S.H., Ahn, S.J., Jeong, G.T., Koh, G.H., Oh, J.H., Kim, H.J., Jeong, W.C., Lee, S.Y., Park, J.H., Ryoo, K.C., Horii, H., Ha, Y.H., Yi, J.H., Cho, W.Y., Kim, Y.T., Lee, K.H., Joo, S.H., Park, S.O., Chung, U.I., Jeong, H.S. and Kim, Kinam, "Full Integration and Reliability Evaluation of Phasechange RAM Based on 0.24 mm-CMOS Technologies," presented at IEEE 2003 Symposium on VLSI Technology, Kyoto, Japan, June 12-14, 2003 K. Horii, H., Yi, J.H., Park, J.H., Ha, Y.H., Baek, I.G., Park, S.O., Hwang, Y.N., Lee, S.H., Kim, Y.T., Lee, K.H., Chung, U-In and Moon, J.T., "A Novel Cell Technology Using N-doped GeSbTe Films for Phase Change RAM," presented at IEEE 2003 Symposium on VLSI Technology, Kyoto, Japan, June 12-14, 2003 Seo, H., Jeong, T.H., Park, J.W., Yeon; C., Kim, S.J., Kim, S.Y., "Investigation of Crystallization Behavior

EXAMINER DATE CONSIDERED

(2000) pp. 745-751, Part 1, No. 2B, February 2000

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

of Sputter-Deposited Nitrogen-Doped Amorphous Ge<sub>2</sub>Sb<sub>2</sub>Te<sub>5</sub> Thin Films", Jpn. J. Appl. Phys., Vol. 39

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